



## ISOLATED 3.3-V FULL AND HALF-DUPLEX RS-485 TRANSCEIVERS

### FEATURES

- 4000- $V_{PEAK}$  Isolation, 560- $V_{peak}$   $V_{IORM}$  UL 1577, IEC 60747-5-2 (VDE 0884, Rev 2)
- 1/8 Unit Load – Up to 256 Nodes on a Bus
- Meets or Exceeds TIA/EIA RS-485 Requirements
- Signaling Rates up to 1 Mbps
- Thermal Shutdown Protection
- Low Bus Capacitance – 16 pF (Typ)
- 50 kV/ $\mu$ s Typical Transient Immunity
- Fail-safe Receiver for Bus Open, Short, Idle
- 3.3-V Inputs are 5-V Tolerant

### APPLICATIONS

- Security Systems
- Chemical Production
- Factory Automation
- Motor/motion Control
- HVAC and Building Automation Networks
- Networked Security Stations

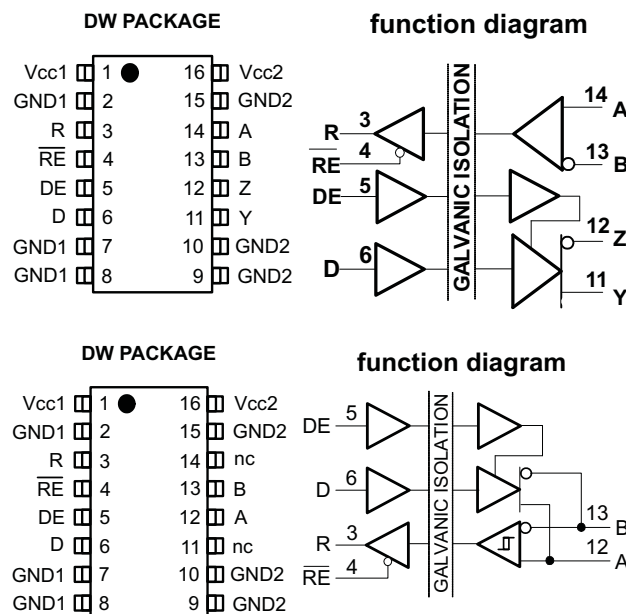
### DESCRIPTION

The ISO15 is an isolated half-duplex differential line transceiver while the ISO35 is an isolated full-duplex differential line driver and receiver for TIA/EIA 485/422 applications.

These devices are ideal for long transmission lines since the ground loop is broken to allow for a much larger common-mode voltage range. The symmetrical isolation barrier of the device is tested to provide 2500 Vrms of isolation for 60s between the bus-line transceiver and the logic-level interface.

Any cabled I/O can be subjected to electrical noise transients from various sources. These noise transients can cause damage to the transceiver and/or near-by sensitive circuitry if they are of sufficient magnitude and duration. These isolated devices can significantly increase protection and reduce the risk of damage to expensive control circuits.

The ISO15 and ISO35 are qualified for use from  $-40^{\circ}\text{C}$  to  $85^{\circ}\text{C}$ .



Please be aware that an important notice concerning availability, standard warranty, and use in critical applications of Texas Instruments semiconductor products and disclaimers thereto appears at the end of this data sheet.



These devices have limited built-in ESD protection. The leads should be shorted together or the device placed in conductive foam during storage or handling to prevent electrostatic damage to the MOS gates.

## ABSOLUTE MAXIMUM RATINGS<sup>(1)</sup>

				VALUE	UNIT	
$V_{CC}$	Input supply voltage. <sup>(2)</sup> $V_{CC1}$ , $V_{CC2}$			-0.3 to 6	V	
$V_O$	Voltage at any bus I/O terminal			-9 to 14	V	
$V_{IT}$	Voltage input, transient pulse, A, B, Y, and Z (through 100 $\Omega$ , see <a href="#">Figure 11</a> )			-50 to 50	V	
$V_I$	Voltage input at any D, DE or $\overline{RE}$ terminal			-0.5 to 7	V	
$I_O$	Receiver output current			$\pm 10$	mA	
ESD	Electrostatic discharge	Human Body Model	JEDEC Standard 22, Test Method A114-C.01	Bus pins and GND1	$\pm 6$	kV
				Bus pins and GND2	$\pm 16$	
		All pins	$\pm 4$			
		Charged Device Model	JEDEC Standard 22, Test Method C101	All pins	$\pm 1$	kV
Machine Model	ANSI/ESDS5.2-1996				$\pm 200$	V
$T_J$	Maximum junction temperature			170	$^{\circ}\text{C}$	

- (1) Stresses beyond those listed under *absolute maximum ratings* may cause permanent damage to the device. These are stress ratings only and functional operation of the device at these or any other conditions beyond those indicated under *recommended operating conditions* is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.
- (2) All voltage values except differential I/O bus voltages are with respect to network ground terminal and are peak voltage values

## RECOMMENDED OPERATING CONDITIONS

				MIN	TYP	MAX	UNIT
$V_{CC}$	Supply Voltage, $V_{CC1}$ , $V_{CC2}$			3.15	3.3	3.6	V
$V_{OC}$	Voltage at either bus I/O terminal	A, B		-7		12	V
$V_{IH}$	High-level input voltage	D, DE, $\overline{RE}$		2		$V_{CC}$	V
$V_{IL}$	Low-level input voltage			0		0.8	
$V_{ID}$	Differential input voltage	A with respect to B		-12		12	V
$R_L$	Differential input resistance			54	60		$\Omega$
$I_O$	Output current	Driver		-60		60	mA
		Receiver		-8		8	
$T_J$	Operating junction temperature			-40		150	$^{\circ}\text{C}$

## SUPPLY CURRENT

over recommended operating condition (unless otherwise noted)

PARAMETER		TEST CONDITIONS		MIN	TYP	MAX	UNIT
$I_{CC1}$	Logic-side supply current	ISO35	$\overline{RE}$ at 0 V or $V_{CC}$ , DE at 0 V, No load (driver disabled)			8	mA
			$\overline{RE}$ at 0 V or $V_{CC}$ , DE at $V_{CC}$ , No Load (driver enabled)			8	
		ISO15	$\overline{RE}$ at 0 V or $V_{CC}$ , DE at 0 V, No load (driver disabled)			8	mA
			$\overline{RE}$ at 0 V or $V_{CC}$ , DE at $V_{CC}$ , No Load (driver enabled)			8	
$I_{CC2}$	Bus-side supply current	ISO35	$\overline{RE}$ at 0 V or $V_{CC}$ , DE at 0 V, No load (driver disabled)			15	mA
			$\overline{RE}$ at 0 V or $V_{CC}$ , DE at $V_{CC}$ , No Load (driver enabled)			19	
		ISO15	$\overline{RE}$ at 0 V or $V_{CC}$ , DE at 0 V, No load (driver disabled)			15	mA
			$\overline{RE}$ at 0 V or $V_{CC}$ , DE at $V_{CC}$ , No Load (driver enabled)			19	

## DRIVER ELECTRICAL CHARACTERISTICS

over recommended operating conditions (unless otherwise noted)

PARAMETER		TEST CONDITIONS	MIN	TYP	MAX	UNIT
V <sub>OD</sub>	Differential output voltage magnitude	I <sub>O</sub> = 0 mA, no load	2.5		V <sub>CC</sub>	V
		R <sub>L</sub> = 54 Ω, See <a href="#">Figure 1</a>	1.5	2		
		R <sub>L</sub> = 100 Ω (RS-422), See <a href="#">Figure 1</a>	2	2.3		
		V <sub>test</sub> from –7 V to +12 V, See <a href="#">Figure 2</a>	1.5			
Δ V <sub>OD</sub>	Change in magnitude of the differential output voltage	See <a href="#">Figure 1</a> and <a href="#">Figure 2</a>	–0.2	0	0.2	V
V <sub>OC(SS)</sub>	Steady-state common-mode output voltage	See <a href="#">Figure 3</a>	1	2.6	3	V
ΔV <sub>OC(SS)</sub>	Change in steady-state common-mode output voltage		–0.1		0.1	
V <sub>OC(pp)</sub>	Peak-to-peak common-mode output voltage	See <a href="#">Figure 3</a>		0.5		V
I <sub>I</sub>	Input current	D, DE, V <sub>I</sub> at 0 V or V <sub>CC1</sub>	–10		10	μA
I <sub>OZ</sub>	High-impedance state output current	ISO15	See receiver input current			μA
		IDO35	V <sub>Y</sub> or V <sub>Z</sub> = 12 V	Other input at 0 V	90	
			V <sub>Y</sub> or V <sub>Z</sub> = 12 V, V <sub>CC</sub> = 0		–10	
			V <sub>Y</sub> or V <sub>Z</sub> = –7 V		90	
V <sub>Y</sub> or V <sub>Z</sub> = –7 V, V <sub>CC</sub> = 0	–10					
I <sub>OS</sub>	Short-circuit output current	V <sub>A</sub> or V <sub>B</sub> at –7 V	Other input at 0 V	–250	250	mA
		V <sub>A</sub> or V <sub>B</sub> at 12 V				
C <sub>(OD)</sub>	Differential output capacitance	V <sub>I</sub> = 0.4 sin(4E6πt) + 0.5 V, DE at 0 V		16		pF
CMTI	Common-mode transient immunity	V <sub>I</sub> = V <sub>CC</sub> or 0 V, See <a href="#">Figure 12</a> and <a href="#">Figure 13</a>	25	50		kV/μs

## DRIVER SWITCHING CHARACTERISTICS

over recommended operating conditions (unless otherwise noted)

PARAMETER		TEST CONDITIONS	MIN	TYP	MAX	UNIT
t <sub>PLH</sub> , t <sub>PHL</sub>	Propagation delay	See <a href="#">Figure 4</a>			340	ns
t <sub>sk(p)</sub>	Pulse skew ( t <sub>PHL</sub> – t <sub>PLH</sub>  )		6			
t <sub>r</sub>	Differential output signal rise time		120	185	300	
t <sub>f</sub>	Differential output signal fall time	See <a href="#">Figure 5</a>	120	180	300	ns
t <sub>PHZ</sub>	Propagation delay, high-level-to-high-impedance output				205	μs
t <sub>PZH</sub>	Propagation delay, high-impedance-to-high-level output	See <a href="#">Figure 6</a>			530	μs
t <sub>PLZ</sub>	Propagation delay, low-level to high-impedance output				330	
t <sub>PZL</sub>	Propagation delay, standby-to-low-level output				530	

## RECEIVER ELECTRICAL CHARACTERISTICS

over recommended operating conditions (unless otherwise noted)

PARAMETER		TEST CONDITIONS	MIN	TYP	MAX	UNIT
$V_{IT(+)}$	Positive-going input threshold voltage	$I_O = -8 \text{ mA}$			-20	mV
$V_{IT(-)}$	Negative-going input threshold voltage	$I_O = 8 \text{ mA}$	-200			mV
$V_{hys}$	Hysteresis voltage ( $V_{IT+} - V_{IT-}$ )			50		mV
$V_O$	Output voltage	$V_{ID} = 200 \text{ mV}$ , See <a href="#">Figure 7</a>	$I_O = -8 \text{ mA}$	2.4		V
			$I_O = 8 \text{ mA}$		0.4	
$I_{O(Z)}$	High-impedance state output current	$V_I = -7 \text{ to } 12 \text{ V}$ , Other input = 0 V	-1		1	$\mu\text{A}$
$I_A$ or $I_B$	Bus input current	$V_A$ or $V_B = 12 \text{ V}$	Other input at 0 V	0.05	0.1	mA
		$V_A$ or $V_B = 12 \text{ V}$ , $V_{CC} = 0$		0.05	0.1	
		$V_A$ or $V_B = -7 \text{ V}$		-0.1	-0.04	
		$V_A$ or $V_B = -7 \text{ V}$ , $V_{CC} = 0$		-0.1	-0.03	
$I_{IH}$	High-level input current, $\overline{RE}$	$V_{IH} = 2 \text{ V}$	-10			$\mu\text{A}$
$I_{IL}$	Low-level input current, $\overline{RE}$	$V_{IL} = 0.8 \text{ V}$	-10			$\mu\text{A}$
$R_{ID}$	Differential input resistance	A, B	48			k $\Omega$
$C_D$	Differential input capacitance	$V_I = 0.4 \sin(4E6\pi t) + 0.5\text{V}$ , DE at 0 V		16		pF

## RECEIVER SWITCHING CHARACTERISTICS

over recommended operating conditions (unless otherwise noted)

PARAMETER		TEST CONDITIONS	MIN	TYP	MAX	UNIT
$t_{PLH}$ , $t_{PHL}$	Propagation delay	ISO15			100	ns
		ISO35			100	
$t_{sk(p)}$	Pulse skew ( $ t_{PHL} - t_{PLH} $ )	ISO15	See <a href="#">Figure 8</a>		13	ns
		ISO35			13	
$t_r$	Output signal rise time			2	4	ns
$t_f$	Output signal fall time			2	4	
$t_{PZH}$ , $t_{PZL}$	Propagation delay, high-impedance-to-high-level output Propagation delay, standby-to-low-level output	DE at 0 V, See <a href="#">Figure 9</a> and <a href="#">Figure 10</a>		13	25	ns
$t_{PHZ}$ , $t_{PLZ}$	Propagation delay, high-level-to-high-impedance output Propagation delay, low-level to high-impedance output			13	25	ns

PARAMETER MEASUREMENT INFORMATION

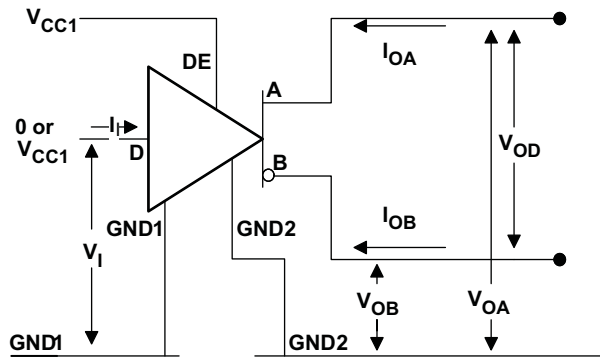


Figure 1. Driver  $V_{OD}$  Test and Current Definitions

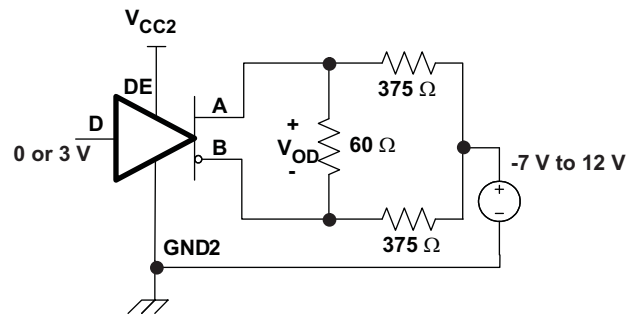


Figure 2. Driver  $V_{OD}$  With Common-Mode Loading Test Circuit

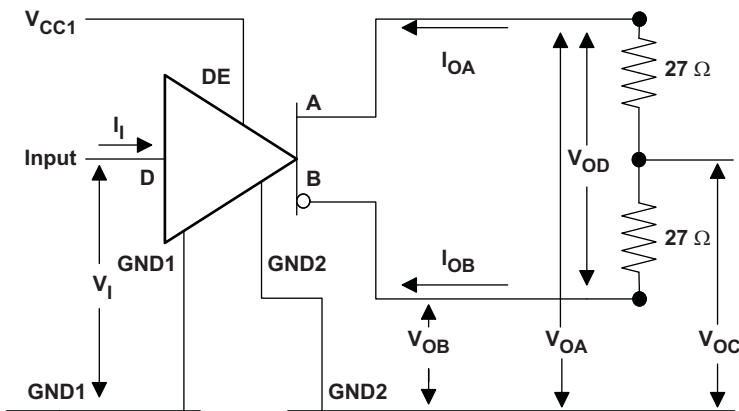
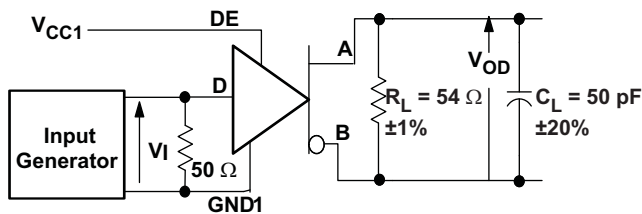


Figure 3. Test Circuit and Waveform Definitions For The Driver Common-Mode Output Voltage



Generator: PRR = 500 kHz, 50% duty cycle,  $t_r < 6\text{ns}$ ,  $t_f < 6\text{ns}$ ,  $Z_0 = 50 \Omega$   $C_L$  includes fixture and Instrumentation Capacitance

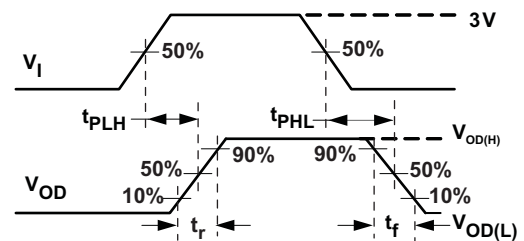


Figure 4. Driver Switching Test Circuit and Voltage Waveforms

PARAMETER MEASUREMENT INFORMATION (continued)

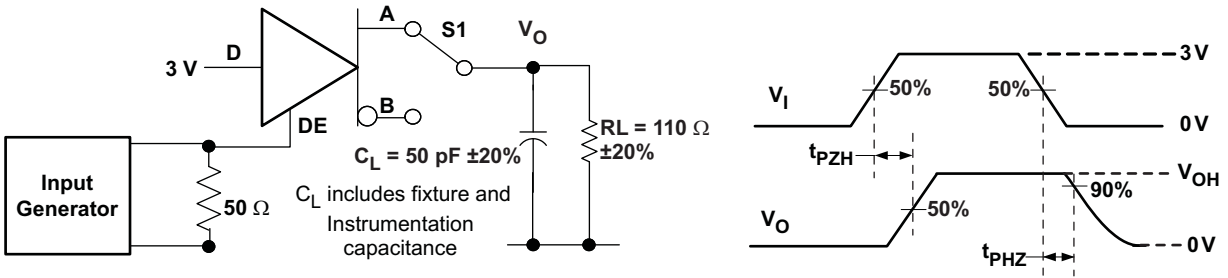


Figure 5. Driver High-Level Output Enable and Disable Time Test Circuit and Voltage Waveforms

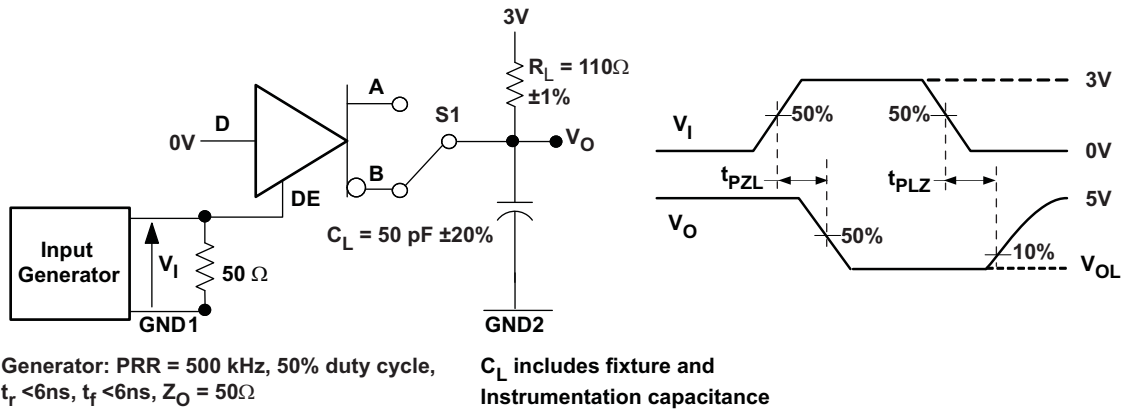


Figure 6. Driver Low-Level Output Enable and Disable Time Test Circuit and Voltage Waveform

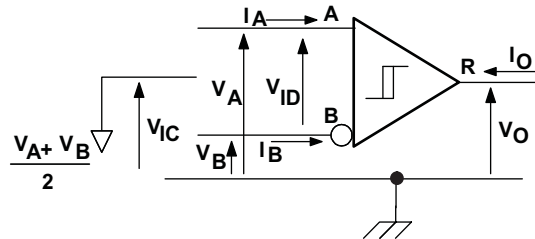


Figure 7. Receiver Voltage and Current Definitions

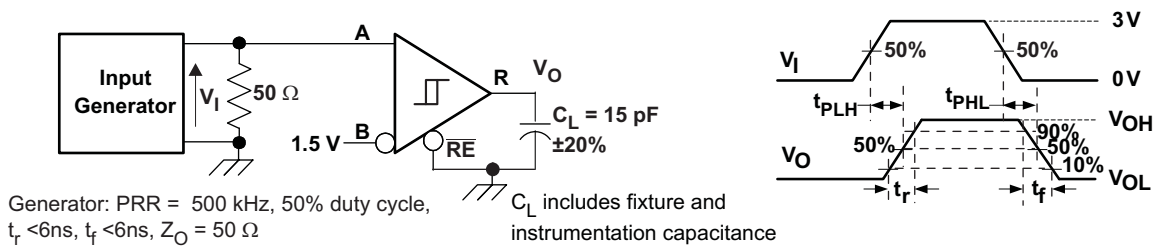


Figure 8. Receiver Switching Test Circuit and Waveforms

PARAMETER MEASUREMENT INFORMATION (continued)

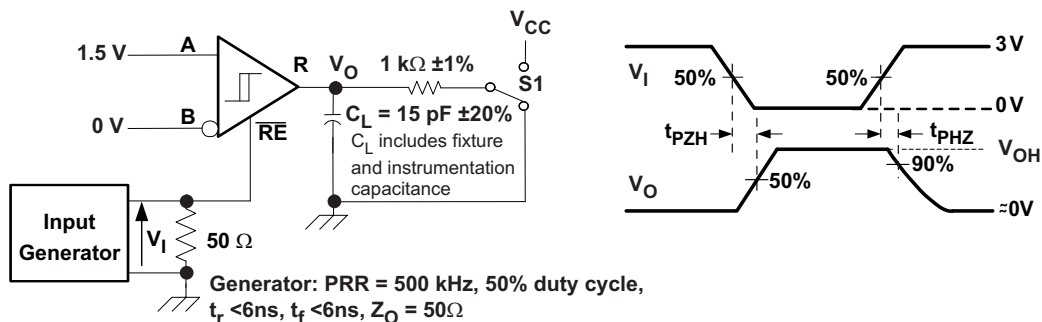


Figure 9. Receiver Enable Test Circuit and Waveforms, Data Output High

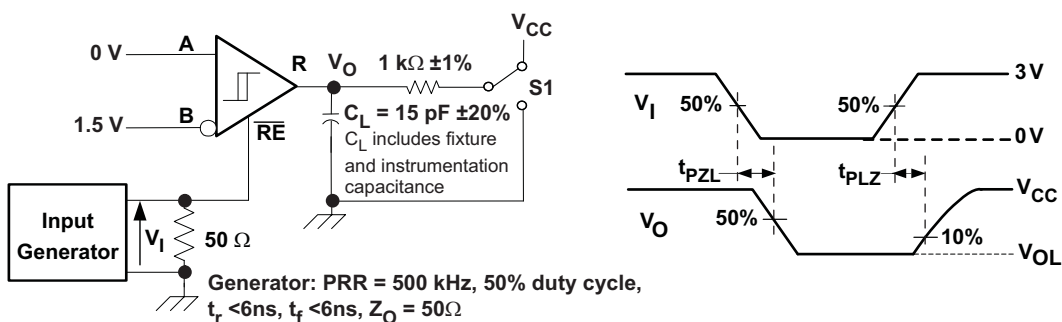
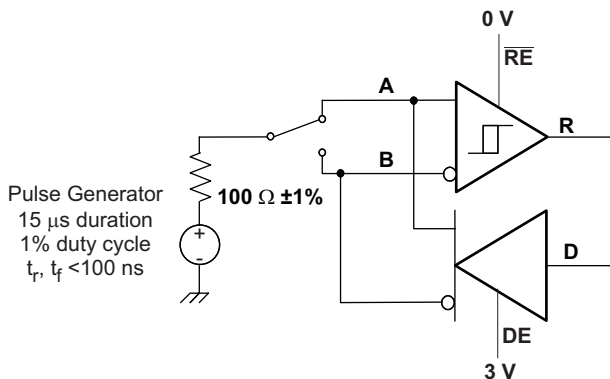


Figure 10. Receiver Enable Test Circuit and Waveforms, Data Output Low



Note: This test is conducted to test survivability only. Data stability at the R output is not specified.

Figure 11. Transient Over-Voltage Test Circuit

PARAMETER MEASUREMENT INFORMATION (continued)

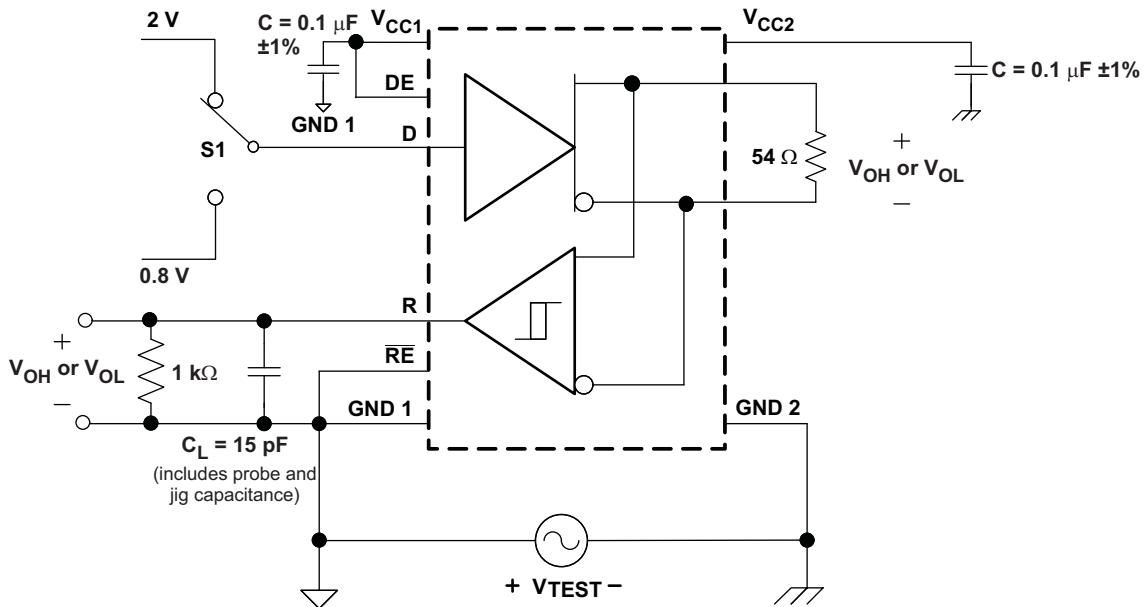


Figure 12. Half-Duplex Common-Mode Transient Immunity Test Circuit

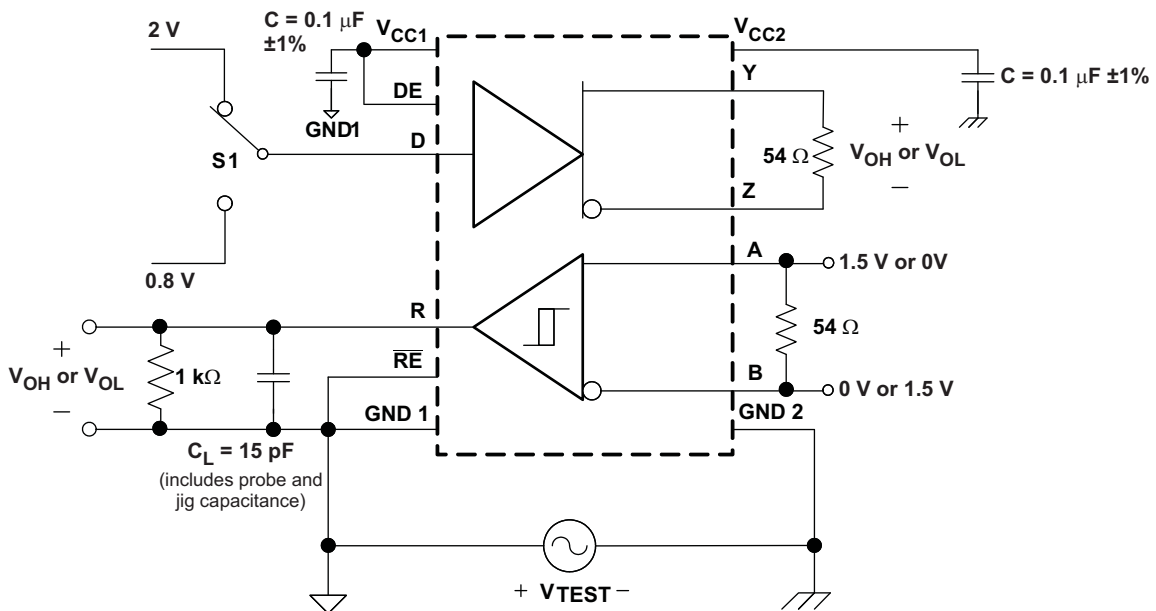


Figure 13. Full-Duplex Common-Mode Transient Immunity Test Circuit



## DEVICE INFORMATION

**Table 1. Driver Function Table**

V <sub>CC1</sub>	V <sub>CC2</sub>	INPUT (D)	ENABLE INPUT (DE)	OUTPUTS	
				A or Y	B or Z
PU	PU	H	H	H	L
PU	PU	L	H	L	H
PU	PU	X	L	Z	Z
PU	PU	X	OPEN	Z	Z
PU	PU	OPEN	H	H	L
PD	PU	X	X	Z	Z
PU	PD	X	X	Z	Z
PD	PD	X	X	Z	Z

**Table 2. Receiver Function Table**

V <sub>CC1</sub>	V <sub>CC2</sub>	DIFFERENTIAL INPUT V <sub>ID</sub> = (V <sub>A</sub> – V <sub>B</sub> )	ENABLE ( $\overline{RE}$ )	OUTPUT (R)
PU	PU	$-0.01\text{ V} \leq V_{ID}$	L	H
PU	PU	$-0.2\text{ V} < V_{ID} < -0.01\text{ V}$	L	?
PU	PU	$V_{ID} \leq -0.2\text{ V}$	L	L
PU	PU	X	H	Z
PU	PU	X	OPEN	Z
PU	PU	Open circuit	L	H
PU	PU	Short Circuit	L	H
PU	PU	Idle (terminated) bus	L	H
PD	PU	X	X	Z
PU	PD	X	L	H

## PACKAGE CHARACTERISTICS

over recommended operating conditions (unless otherwise noted)

PARAMETER <sup>(1)</sup>		TEST CONDITIONS	MIN	TYP	MAX	UNIT
L(I01)	Minimum air gap (Clearance)	Shortest terminal to terminal distance through air	8.34			mm
L(I02)	Minimum external tracking (Creepage)	Shortest terminal to terminal distance across the package surface	8.1			mm
CTI	Tracking resistance (Comparative Tracking Index)	DIN IEC 60112 / VDE 0303 Part 1	≥175			V
	Minimum Internal Gap (Internal Clearance)	Distance through the insulation	0.008			mm
R <sub>IO</sub>	Isolation resistance	Input to output, V <sub>IO</sub> = 500 V, all pins on each side of the barrier tied together creating a two-terminal device		>10 <sup>12</sup>		Ω
C <sub>IO</sub>	Barrier capacitance Input to output	V <sub>1</sub> = 0.4 sin (4E6πt)		2		pF
C <sub>1</sub>	Input capacitance to ground	V <sub>1</sub> = 0.4 sin (4E6πt)		2		pF

(1) Creepage and clearance requirements should be applied according to the specific equipment isolation standards of an application. Care should be taken to maintain the creepage and clearance distance of a board design to ensure that the mounting pads of the isolator on the printed circuit board do not reduce this distance.

Creepage and clearance on a printed circuit board become equal according to the measurement techniques shown in the Isolation Glossary. Techniques such as inserting grooves and/or ribs on a printed circuit board are used to help increase these specifications.

### IEC 60664-1 RATINGS TABLE

PARAMETER	TEST CONDITIONS	SPECIFICATION
Basic isolation group	Material group	IIIa
Installation classification	Rated mains voltage $\leq 150 V_{RMS}$	I-IV
	Rated mains voltage $\leq 300 V_{RMS}$	I-III
	Rated mains voltage $\leq 400 V_{RMS}$	I-II

### IEC 60747-5-2 INSULATION CHARACTERISTICS <sup>(1)</sup>

over recommended operating conditions (unless otherwise noted)

PARAMETER		TEST CONDITIONS	SPECIFICATION	UNIT
$V_{IORM}$	Maximum working insulation voltage		560	V
$V_{PR}$	Input to output test voltage	Method b1, $V_{PR} = V_{IORM} \times 1.875$ , 100% Production test with $t = 1$ s, Partial discharge $< 5$ pC	1050	V
$V_{IOTM}$	Transient overvoltage	$t = 60$ s	4000	V
$R_S$	Insulation resistance	$V_{IO} = 500$ V at $T_S$	$>10^9$	$\Omega$
	Pollution degree		2	

(1) Climatic Classification 40/125/21

### REGULATORY INFORMATION

VDE	UL
Certified according to IEC 60747-5-2	Recognized under 1577 Component Recognition Program <sup>(1)</sup>
File Number: 40016131	File Number: E181974

(1) Production tested  $\geq 3000$  VRMS for 1 second in accordance with UL 1577.

## IEC SAFETY LIMITING VALUES

Safety limiting intends to prevent potential damage to the isolation barrier upon failure of input or output circuitry. A failure of the IO can allow low resistance to ground or the supply and, without current limiting, dissipate sufficient power to overheat the die and damage the isolation barrier potentially leading to secondary system failures.

PARAMETER		TEST CONDITIONS		MIN	TYP	MAX	UNIT
$I_S$	Safety input, output, or supply current	DW-16	$\theta_{JA} = 212^\circ\text{C/W}$ , $V_I = 5.5\text{ V}$ , $T_J = 170^\circ\text{C}$ , $T_A = 25^\circ\text{C}$			210	mA
$T_S$	Maximum case temperature	DW-16				150	$^\circ\text{C}$

The safety-limiting constraint is the absolute maximum junction temperature specified in the absolute maximum ratings table. The power dissipation and junction-to-air thermal impedance of the device installed in the application hardware determines the junction temperature. The assumed junction-to-air thermal resistance in the Thermal Characteristics table is that of a device installed in the JESD51-3, Low Effective Thermal Conductivity Test Board for Leaded Surface Mount Packages and is conservative. The power is the recommended maximum input voltage times the current. The junction temperature is then the ambient temperature plus the power times the junction-to-air thermal resistance.

## THERMAL CHARACTERISTICS

over recommended operating conditions (unless otherwise noted)

PARAMETER		TEST CONDITIONS		MIN	TYP	MAX	UNIT
$\theta_{JA}$	Junction-to-Air	Low-K Thermal Resistance <sup>(1)</sup>			168		$^\circ\text{C/W}$
		High-K Thermal Resistance			96.1		
$\theta_{JB}$	Junction-to-Board Thermal Resistance				61		$^\circ\text{C/W}$
$\theta_{JC}$	Junction-to-Case Thermal Resistance				48		$^\circ\text{C/W}$
$P_D$	Device Power Dissipation	$V_{CC1} = V_{CC2} = 5.25\text{ V}$ , $T_J = 150^\circ\text{C}$ , $C_L = 15\text{ pF}$ , Input a 20 MHz 50% duty cycle square wave				220	mW

(1) Tested in accordance with the Low-K or High-K thermal metric definitions of EIA/JESD51-3 for leaded surface mount packages.

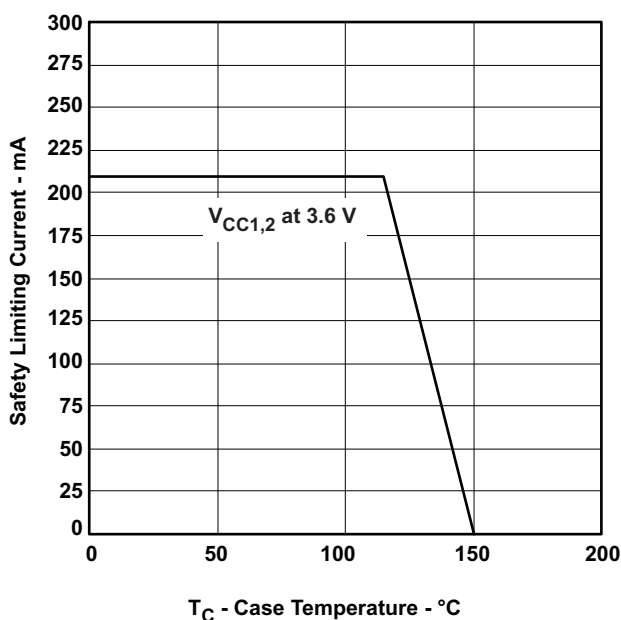
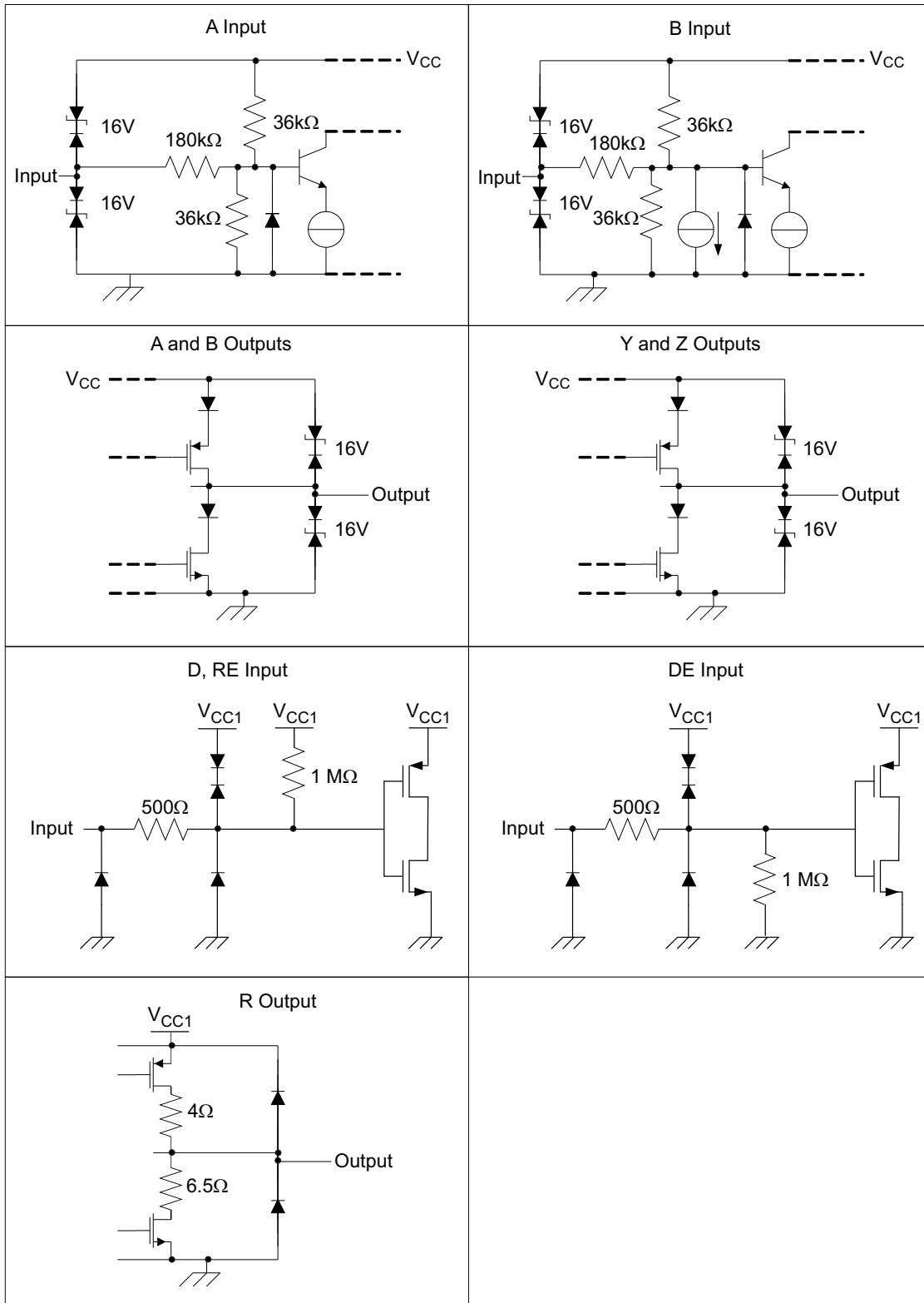


Figure 14. DW-16  $\theta_{JC}$  Thermal Derating Curve per IEC 60747-5-2

EQUIVALENT CIRCUIT SCHEMATICS



TYPICAL CHARACTERISTICS CURVES

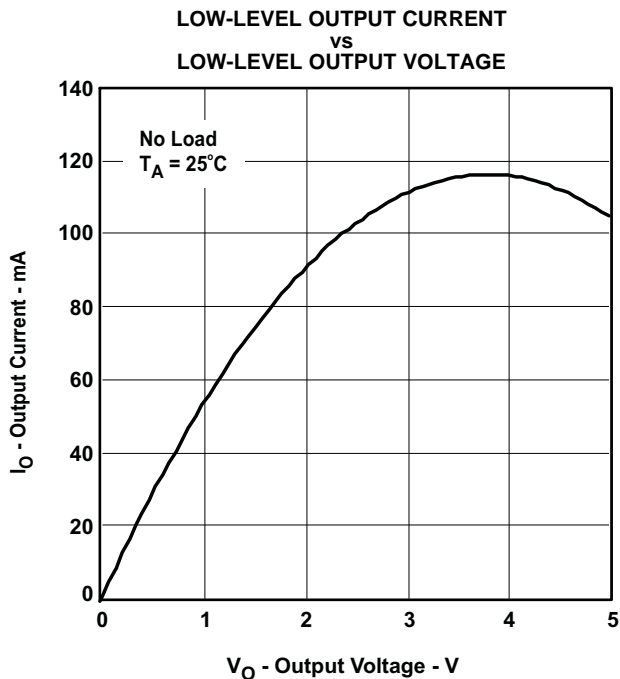


Figure 15.

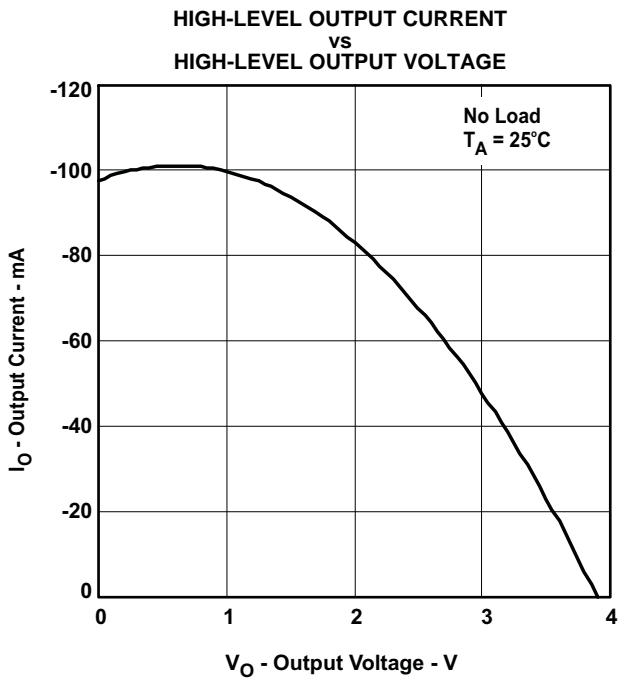


Figure 16.

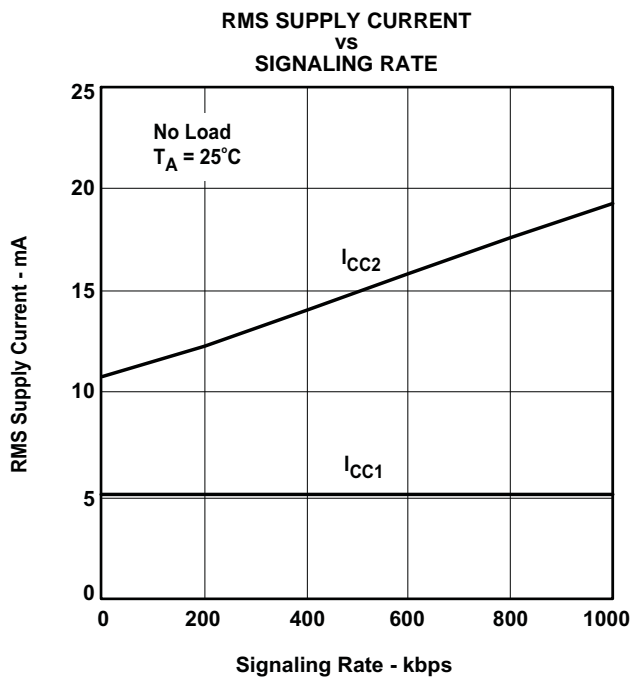


Figure 17.

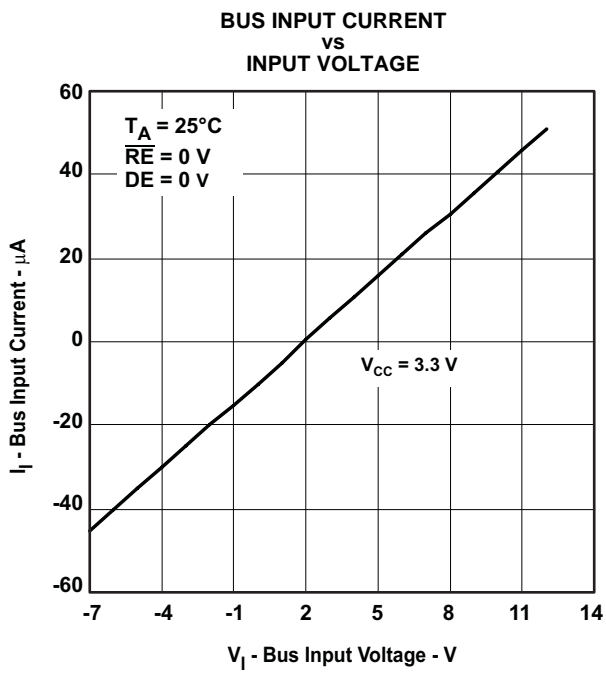
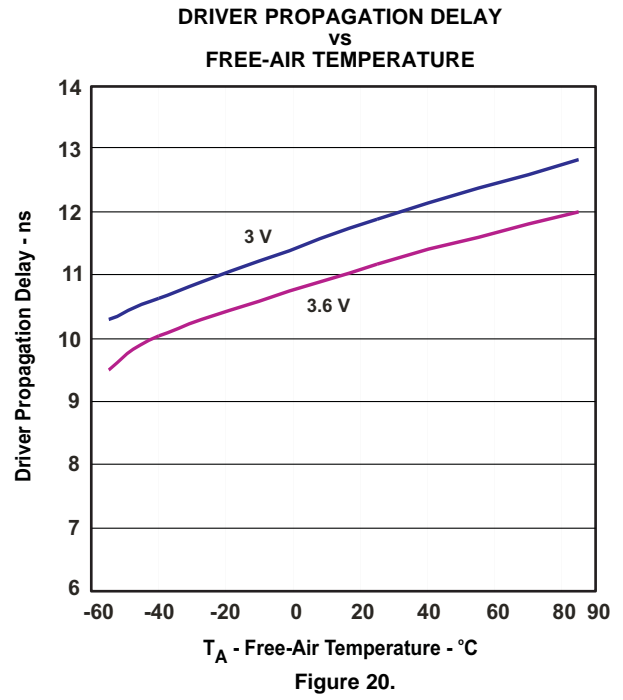
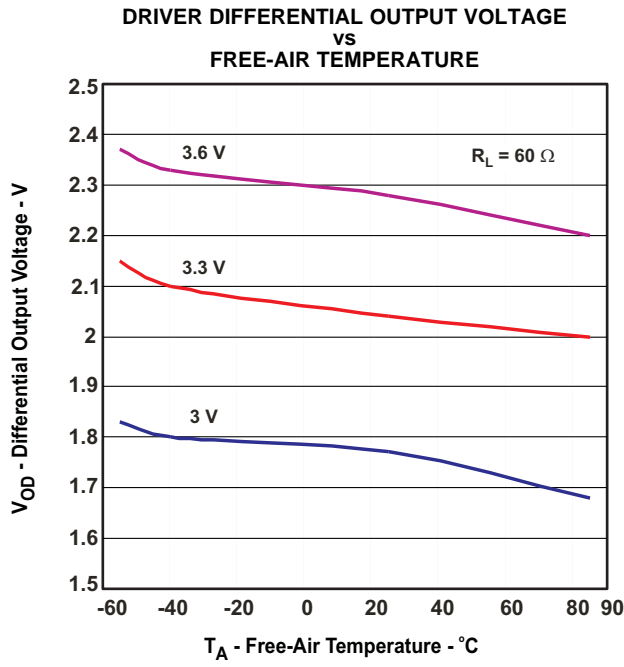


Figure 18.

TYPICAL CHARACTERISTICS CURVES (continued)



## APPLICATION INFORMATION

### Transient Voltages

Isolation of a circuit insulates it from other circuits and earth so that noise develops across the insulation rather than circuit components. The most common noise threat to data-line circuits is voltage surges or electrical fast transients that occur after installation. The transient ratings of the ISO15 and ISO35 are sufficient for all but the most severe installations. However, some equipment manufacturers use their ESD generators to test transient susceptibility of their equipment, and can exceed insulation ratings. ESD generators simulate static discharges that may occur during device or equipment handling with low-energy but high voltage transients.

Figure 21 models the ISO15 and ISO35 bus IO connected to a noise generator.  $C_{IN}$  and  $R_{IN}$  is capacitance or resistance across the device and any other stray or added capacitance or resistance across the A or B pin to GND2.  $C_{ISO}$  and  $R_{ISO}$  is the capacitance and resistance between GND1 and GND2 of the ISO15 and ISO35 plus those of any other insulation (transformer, etc.). The stray inductance is assumed to be negligible. From this model, the voltage at the isolated bus return is,

$$V_{GND2} = V_N \frac{Z_{ISO}}{Z_{ISO} + Z_{IN}} \quad (1)$$

and will always be less than 16 V from  $V_N$ . If the ISO15 and ISO35 are tested as a stand-alone device,  $R_{IN} = 6 \times 10^4 \Omega$ ,  $C_{IN} = 16 \times 10^{-12}$  F,  $R_{ISO} = 10^9 \Omega$  and  $C_{ISO} = 10^{-12}$  F.

Note from Figure 21 that the resistor ratio determines the voltage ratio at low frequency and it is the inverse capacitance ratio at high frequency. In the stand-alone case and for low frequency,

$$\frac{V_{GND2}}{V_N} = \frac{R_{ISO}}{R_{ISO} + R_{IN}} = \frac{10^9}{10^9 + 6 \times 10^4} \quad (2)$$

or essentially all of noise appears across the barrier. At high frequency,

$$\frac{V_{GND2}}{V_N} = \frac{\frac{1}{C_{ISO}}}{\frac{1}{C_{ISO}} + \frac{1}{C_{IN}}} = \frac{1}{1 + \frac{C_{ISO}}{C_{IN}}} = \frac{1}{1 + \frac{1}{16}} = 0.94 \quad (3)$$

and 94% of  $V_N$  appears across the barrier. As long as  $R_{ISO}$  is greater than  $R_{IN}$  and  $C_{ISO}$  is less than  $C_{IN}$ , most of transient noise appears across the isolation barrier.

It is not recommend for the user to test equipment transient susceptibility with ESD generators, or consider product claims of ESD ratings above the barrier transient ratings of an isolated interface. ESD is best managed through recessing or covering connector pins in a conductive connector shell and installer training.

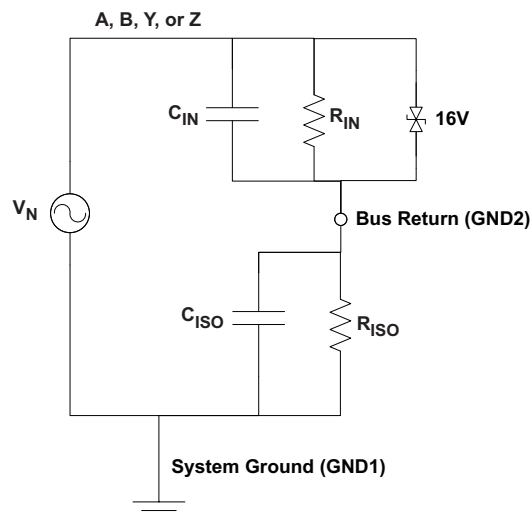


Figure 21. Noise Model

**PACKAGING INFORMATION**

Orderable Device	Status <sup>(1)</sup>	Package Type	Package Drawing	Pins	Package Qty	Eco Plan <sup>(2)</sup>	Lead/Ball Finish	MSL Peak Temp <sup>(3)</sup>
ISO15DW	ACTIVE	SOIC	DW	16	40	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-2-260C-1 YEAR
ISO15DWG4	ACTIVE	SOIC	DW	16	40	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-2-260C-1 YEAR
ISO15DWR	ACTIVE	SOIC	DW	16	2000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-2-260C-1 YEAR
ISO15DWRG4	ACTIVE	SOIC	DW	16	2000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-2-260C-1 YEAR
ISO35DW	ACTIVE	SOIC	DW	16	40	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-2-260C-1 YEAR
ISO35DWG4	ACTIVE	SOIC	DW	16	40	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-2-260C-1 YEAR
ISO35DWR	ACTIVE	SOIC	DW	16	2000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-2-260C-1 YEAR
ISO35DWRG4	ACTIVE	SOIC	DW	16	2000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-2-260C-1 YEAR

<sup>(1)</sup> The marketing status values are defined as follows:

**ACTIVE:** Product device recommended for new designs.

**LIFEBUY:** TI has announced that the device will be discontinued, and a lifetime-buy period is in effect.

**NRND:** Not recommended for new designs. Device is in production to support existing customers, but TI does not recommend using this part in a new design.

**PREVIEW:** Device has been announced but is not in production. Samples may or may not be available.

**OBSOLETE:** TI has discontinued the production of the device.

<sup>(2)</sup> Eco Plan - The planned eco-friendly classification: Pb-Free (RoHS), Pb-Free (RoHS Exempt), or Green (RoHS & no Sb/Br) - please check <http://www.ti.com/productcontent> for the latest availability information and additional product content details.

**TBD:** The Pb-Free/Green conversion plan has not been defined.

**Pb-Free (RoHS):** TI's terms "Lead-Free" or "Pb-Free" mean semiconductor products that are compatible with the current RoHS requirements for all 6 substances, including the requirement that lead not exceed 0.1% by weight in homogeneous materials. Where designed to be soldered at high temperatures, TI Pb-Free products are suitable for use in specified lead-free processes.

**Pb-Free (RoHS Exempt):** This component has a RoHS exemption for either 1) lead-based flip-chip solder bumps used between the die and package, or 2) lead-based die adhesive used between the die and leadframe. The component is otherwise considered Pb-Free (RoHS compatible) as defined above.

**Green (RoHS & no Sb/Br):** TI defines "Green" to mean Pb-Free (RoHS compatible), and free of Bromine (Br) and Antimony (Sb) based flame retardants (Br or Sb do not exceed 0.1% by weight in homogeneous material)

<sup>(3)</sup> MSL, Peak Temp. -- The Moisture Sensitivity Level rating according to the JEDEC industry standard classifications, and peak solder temperature.

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**TAPE AND REEL INFORMATION**



**QUADRANT ASSIGNMENTS FOR PIN 1 ORIENTATION IN TAPE**



\*All dimensions are nominal

Device	Package Type	Package Drawing	Pins	SPQ	Reel Diameter (mm)	Reel Width W1 (mm)	A0 (mm)	B0 (mm)	K0 (mm)	P1 (mm)	W (mm)	Pin1 Quadrant
ISO15DWR	SOIC	DW	16	2000	330.0	16.4	10.75	10.7	2.7	12.0	16.0	Q1
ISO35DWR	SOIC	DW	16	2000	330.0	16.4	10.75	10.7	2.7	12.0	16.0	Q1

**TAPE AND REEL BOX DIMENSIONS**

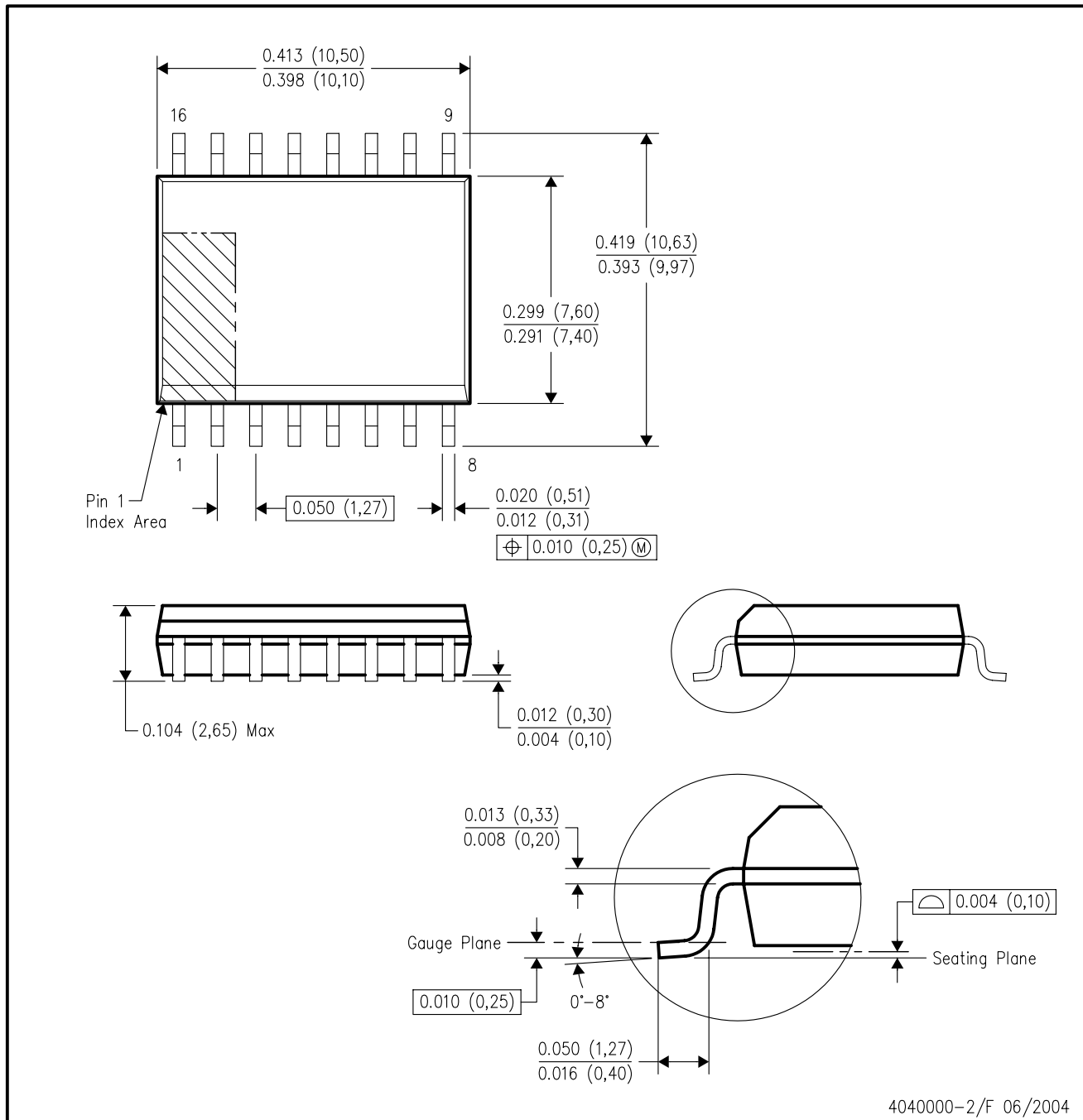


\*All dimensions are nominal

Device	Package Type	Package Drawing	Pins	SPQ	Length (mm)	Width (mm)	Height (mm)
ISO15DWR	SOIC	DW	16	2000	358.0	335.0	35.0
ISO35DWR	SOIC	DW	16	2000	358.0	335.0	35.0

DW (R-PDSO-G16)

PLASTIC SMALL-OUTLINE PACKAGE



4040000-2/F 06/2004

- NOTES:
- A. All linear dimensions are in inches (millimeters).
  - B. This drawing is subject to change without notice.
  - C. Body dimensions do not include mold flash or protrusion not to exceed 0.006 (0,15).
  - D. Falls within JEDEC MS-013 variation AA.

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